

# DATA SHEET

## **74LVT32374**

**3.3 V 32-bit edge-triggered D-type  
flip-flop; 3-state**

Product specification  
Supersedes data of 2002 Mar 20

2004 Oct 15

### 3.3 V 32-bit edge-triggered D-type flip-flop; 3-state

## 74LVT32374

#### FEATURES

- 32-bit edge-triggered flip-flop
- 3-state buffers
- Output capability: +64 mA/–32 mA
- TTL input and output switching levels
- Input and output interface capability to systems at 5 V supply
- Bus-hold data inputs eliminate the need for external pull-up resistors to hold unused inputs
- Live insertion/extraction permitted
- Power-up reset
- Power-up 3-state
- No bus current loading when output is tied to 5 V bus
- Latch-up protection exceeds 500 mA in accordance with JEDEC std 17
- ESD protection exceeds 2000 V in accordance with MIL STD 883 method 3015 and 200 V in accordance with machine model.

#### DESCRIPTION

The 74LVT32374 is a high-performance BICMOS product designed for  $V_{CC}$  operation at 3.3 V.

The 74LVT32374 is a 32-bit edge-triggered D-type flip-flop featuring non-inverting 3-state outputs. The device can be used as four 8-bit flip-flops, or two 16-bit flip-flops or one 32-bit flip-flop. On the positive transition of the clock (CP), the Q outputs of the flip-flop take on the logic levels set-up at the D inputs.

#### QUICK REFERENCE DATA

GND = 0 V;  $T_{amb} = 25\text{ }^{\circ}\text{C}$ ;  $t_r = t_f \leq 2.5\text{ ns}$ .

SYMBOL	PARAMETER	CONDITIONS	TYPICAL	UNIT
$t_{PHL}/t_{PLH}$	propagation delay nCP to nQ <sub>n</sub>	$C_L = 50\text{ pF}$ ; $V_{CC} = 3.3\text{ V}$	2.9	ns
$C_I$	input capacitance	$V_I = 0\text{ V}$ or $3.0\text{ V}$	3	pF
$C_O$	output capacitance	outputs disabled; $V_O = 0\text{ V}$ or $3.0\text{ V}$	9	pF
$I_{CCZ}$	total supply current	output disabled; $V_{CC} = 3.6\text{ V}$	140	$\mu\text{A}$

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#### FUNCTION TABLE

See note 1.

OPERATING MODE	INPUT			INTERNAL REGISTER	OUTPUT
	nOE	nCP	nD <sub>n</sub>		nQ <sub>n</sub>
Load and read register	L	↑	l	L	L
	L	↑	h	H	H
Hold	L	↑ +	X	NC	NC
Disable outputs	H	↑ +	X	NC	Z
	H	↑	nD <sub>n</sub>	nD <sub>n</sub>	Z

#### Note

1. H = HIGH voltage level;  
h = HIGH voltage level one set-up time prior to the HIGH-to-LOW OE transition;  
L = LOW voltage level;  
l = LOW voltage level one set-up time prior to the HIGH-to-LOW OE transition;  
NC = not connected;  
X = don't care;  
Z = high-impedance OFF-state;  
↑ = LOW-to-HIGH CP transition;  
↑  
+ = not a LOW-to-HIGH CP transition.

#### ORDERING INFORMATION

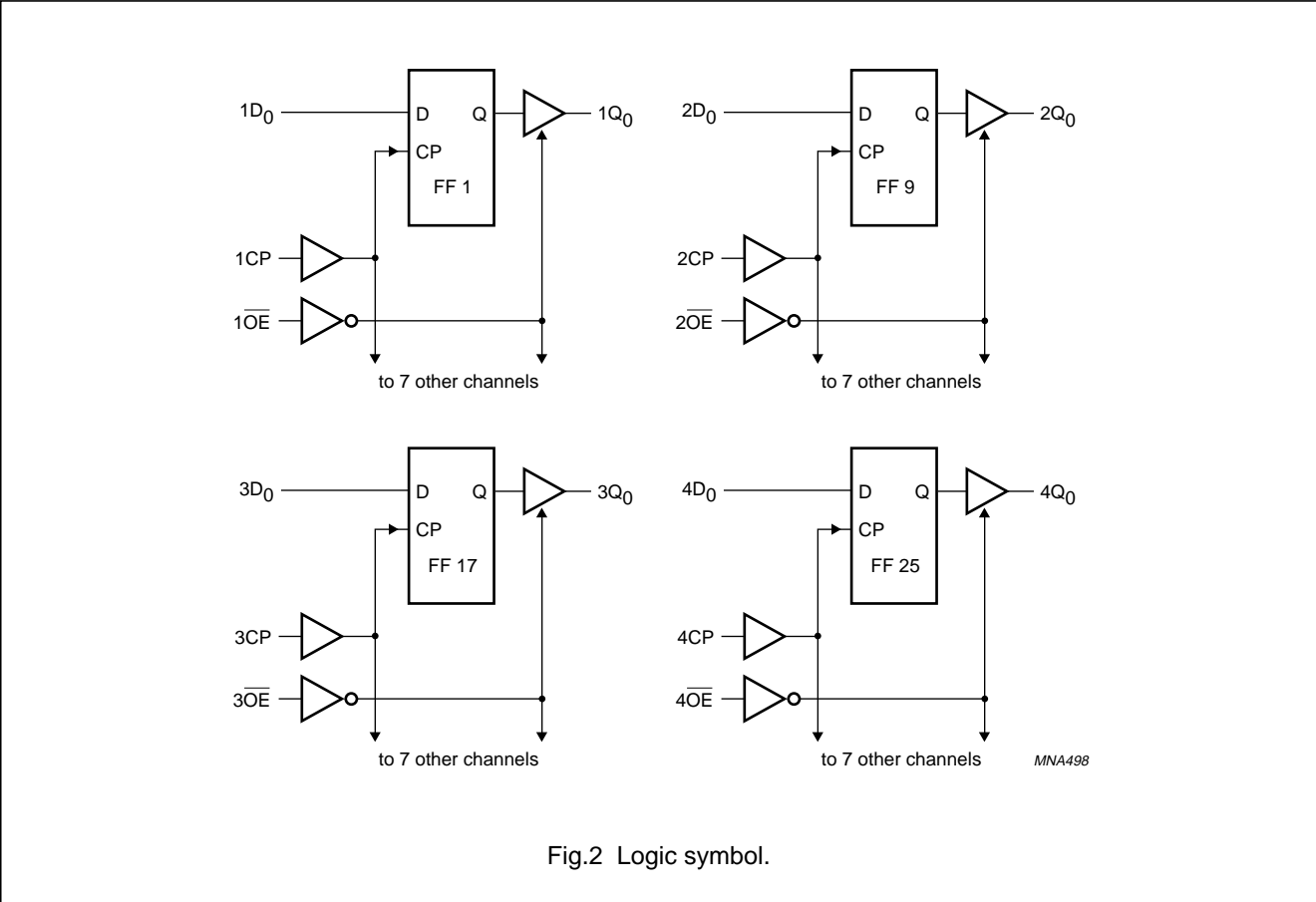
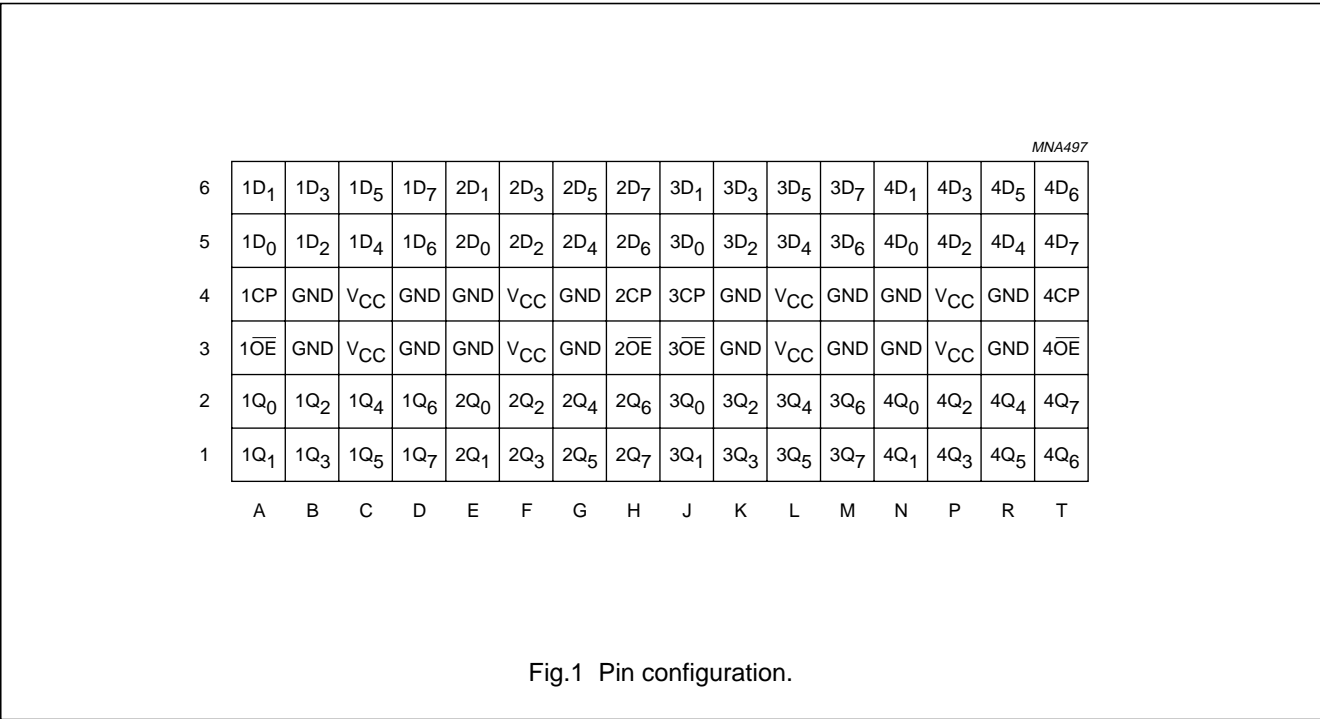
TYPE NUMBER	TEMPERATURE RANGE	PACKAGE			
		PINS	PACKAGE	MATERIAL	CODE
74LVT32374EC	−40 °C to +85 °C	96	LFBGA96	plastic	SOT536-1

#### PINNING

SYMBOL	DESCRIPTION
nD <sub>n</sub>	data input
nCP	clock input
nQ <sub>n</sub>	flip-flop output
GND	ground (0 V)
nOE	output enable input (active LOW)
V <sub>CC</sub>	supply voltage

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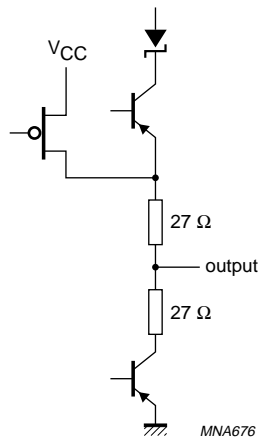


Fig.3 Schematic of each output.

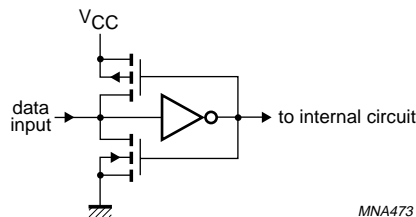


Fig.4 Bus hold circuit.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>CC</sub>	supply voltage		2.7	+3.6	V
V <sub>I</sub>	input voltage	note 1	0	5.5	V
V <sub>IH</sub>	HIGH-level input voltage		2.0	–	V
V <sub>IL</sub>	LOW-level input voltage		–	0.8	V
I <sub>OH</sub>	HIGH-level output current		–	–32	mA
I <sub>OL</sub>	LOW-level output current		–	32	mA
		current duty cycle ≤ 50 %; f ≥ 1 kHz	–	64	mA
Δt/ΔV	input transition rise or fall times	outputs enabled	–	10	ns/V
T <sub>amb</sub>	ambient temperature		–40	+85	°C
P <sub>tot</sub>	power dissipation per package	note 2	–	1000	mW

Notes

1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. Above 70 °C the value of P<sub>tot</sub> derates linearly with 1.8 mW/K.

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#### LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134); note 1.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{CC}$	supply voltage		-0.5	–	+4.6	V
$I_{IK}$	input diode current	$V_I < 0$ V	–	-50	–	mA
$V_I$	input voltage	note 2	-0.5	–	+7.0	V
$I_{OK}$	output diode current		–	-50	–	mA
$V_O$	output voltage	output in OFF or HIGH state; note 2	-0.5	–	+7.0	V
$I_O$	output current	output in LOW state	–	128	–	mA
		output in HIGH state	–	-64	–	mA
$T_{stg}$	storage temperature		-65	–	+150	°C

#### Notes

1. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.
2. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

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#### DC CHARACTERISTICS

Over recommended operating conditions; voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	TEST CONDITIONS		MIN.	TYP. <sup>(1)</sup>	MAX.	UNIT
		OTHER	V <sub>CC</sub> (V)				
T <sub>amb</sub> = −40 °C to +85 °C							
V <sub>IK</sub>	input clamp voltage	I <sub>IK</sub> = −18 mA	2.7	−	−0.85	−1.2	V
V <sub>OH</sub>	HIGH-level output voltage	I <sub>OH</sub> = −32 mA	3.0	2.0	2.3	−	V
V <sub>OL</sub>	LOW-level output voltage	I <sub>OL</sub> = 64 mA	3.0	−	0.4	0.55	V
V <sub>RST</sub>	power-up output LOW voltage	I <sub>O</sub> = −1 mA; V <sub>I</sub> = GND or V <sub>CC</sub> ; note 2	3.6	−	0.1	0.55	V
I <sub>LI</sub>	input leakage current	V <sub>I</sub> = V <sub>CC</sub> or GND; control pins	3.6	−	0.1	±1	μA
		V <sub>I</sub> = 5.5 V	0 or 3.6	−	0.4	10	μA
		V <sub>I</sub> = V <sub>CC</sub> ; data pins; note 3	3.6	−	0.1	1	μA
		V <sub>I</sub> = 0 V; data pins; note 3	3.6	−	−0.4	−5	μA
I <sub>off</sub>	output OFF current	V <sub>I</sub> or V <sub>O</sub> = 0 V to 4.5 V	0	−	0.1	±100	μA
I <sub>hold</sub>	bus hold current D inputs	V <sub>I</sub> = 0.8 V; note 4	3.0	75	135	−	μA
		V <sub>I</sub> = 2.0 V; note 4	3.0	−75	−135	−	μA
		V <sub>CC</sub> = 3.6 V; note 4	0 to 3.6	±500	−	−	μA
I <sub>EX</sub>	current into an output in the HIGH state when V <sub>O</sub> > V <sub>CC</sub>	V <sub>O</sub> = 5.5 V	3.0	−	50	125	μA
I <sub>pu/pd</sub>	power-up/down 3-state output current	V <sub>O</sub> = 5.5 V to V <sub>CC</sub> ; V <sub>I</sub> = GND or V <sub>CC</sub> ; V <sub>OE</sub> = don't care; note 5	≤ 1.2 V	−	1	±100	μA
I <sub>OZH</sub>	3-state output HIGH current	V <sub>O</sub> = 3.0 V; V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	3.6	−	0.5	5	μA
I <sub>OZL</sub>	3-state output LOW current	V <sub>O</sub> = 0.5 V; V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	3.6	−	+0.5	−5	μA
I <sub>CCH</sub>	quiescent supply current	outputs HIGH; I <sub>O</sub> = 0 A; V <sub>I</sub> = GND or V <sub>CC</sub>	3.6	−	0.14	0.24	mA
I <sub>CCL</sub>	quiescent supply current	outputs LOW; I <sub>O</sub> = 0 A; V <sub>I</sub> = GND or V <sub>CC</sub>	3.6	−	8	12	mA
I <sub>CCZ</sub>	quiescent supply current	outputs disabled; I <sub>O</sub> = 0 A; V <sub>I</sub> = GND or V <sub>CC</sub> ; note 6	3.6	−	0.14	0.24	mA
ΔI <sub>CC</sub>	additional supply current per input pin	one input at V <sub>CC</sub> − 0.6 V; other inputs at GND or V <sub>CC</sub> ; note 7	3.0 to 3.6	−	0.1	0.2	μA

#### Notes

1. All typical values are measured at V<sub>CC</sub> = 3.3 V and T<sub>amb</sub> = 25 °C.
2. For valid test results, data must not be loaded into the flip-flops (or latches) after applying power.
3. Unused pins at V<sub>CC</sub> or GND.
4. This is the bus hold overdrive current required to force the input to the opposite logic state.
5. This parameter is valid for any V<sub>CC</sub> between 0 V and 1.2 V with a transition time of up to 10 ms. From V<sub>CC</sub> = 1.2 V to V<sub>CC</sub> = 3.3 V ± 0.3 V a transition time of 100 μs is permitted. This parameter is valid for T<sub>amb</sub> = 25 °C only.
6. I<sub>CCZ</sub> is measured with outputs pulled to V<sub>CC</sub> or GND.
7. This is the increase in supply current for each input at the specified voltage level other than V<sub>CC</sub> or GND.

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#### AC CHARACTERISTICS

GND = 0 V;  $t_r = t_f \leq 2.5$  ns;  $C_L = 50$  pF;  $R_L = 500 \Omega$ .

SYMBOL	PARAMETER	CONDITIONS		MIN.	TYP. <sup>(1)</sup>	MAX.	UNIT
		WAVEFORMS	V <sub>CC</sub> (V)				
T <sub>amb</sub> = −40 °C to +85 °C							
t <sub>PLH</sub>	propagation delay nCP to nQ <sub>n</sub>	see Fig.5	2.7	—	—	6.2	ns
			3.0 to 3.6	1.5	3.0	5.3	ns
t <sub>PHL</sub>	propagation delay nCP to nQ <sub>n</sub>	see Fig.5	2.7	—	—	5.1	ns
			3.0 to 3.6	1.5	3.0	4.9	ns
t <sub>PZH</sub>	output enable time to HIGH level	see Figs 7 and 8	2.7	—	—	6.9	ns
			3.0 to 3.6	1.5	3.5	5.6	ns
t <sub>PZL</sub>	output enable time to LOW level	see Figs 7 and 8	2.7	—	—	6.0	ns
			3.0 to 3.6	1.5	3.2	4.9	ns
t <sub>PHZ</sub>	output disable time from HIGH level	see Figs 7 and 8	2.7	—	—	5.7	ns
			3.0 to 3.6	1.5	3.5	5.4	ns
t <sub>PLZ</sub>	output disable time from LOW level	see Figs 7 and 8	2.7	1.5	3.2	5.1	ns
			3.0 to 3.6	1.5	3.2	5.0	ns
t <sub>suH</sub>	set-up time nD <sub>n</sub> HIGH to nCP	see Fig.6	2.7	2.0	—	—	ns
			3.0 to 3.6	2.0	0.7	—	ns
t <sub>suL</sub>	set-up time nD <sub>n</sub> LOW to nCP	see Fig.6	2.7	2.0	—	—	ns
			3.0 to 3.6	2.0	0.7	—	ns
t <sub>hH</sub>	hold time nD <sub>n</sub> HIGH to nCP	see Fig.6	2.7	0.1	—	—	ns
			3.0 to 3.6	0.8	0	—	ns
t <sub>hL</sub>	hold time nD <sub>n</sub> LOW to nCP	see Fig.6	2.7	0.1	—	—	ns
			3.0 to 3.6	0.8	0	—	ns
t <sub>WH</sub>	nCP HIGH pulse width	see Fig.6	2.7	1.5	—	—	ns
			3.0 to 3.6	1.5	0.6	—	ns
t <sub>WL</sub>	nCP LOW pulse width	see Fig.6	2.7	3.0	—	—	ns
			3.0 to 3.6	3.0	1.6	—	ns
f <sub>max</sub>	maximum clock pulse frequency	see Fig.5	3.0 to 3.6	150	—	—	MHz

#### Note

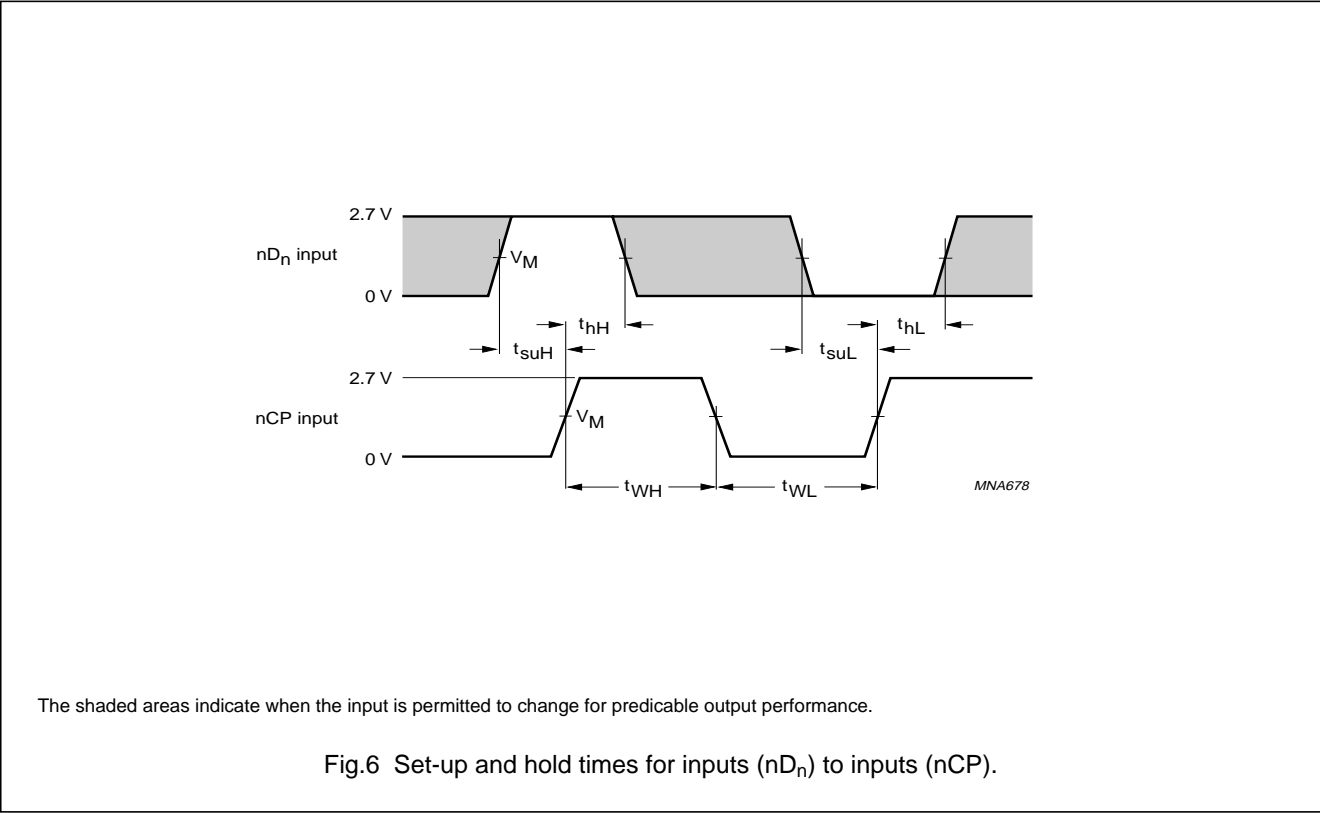
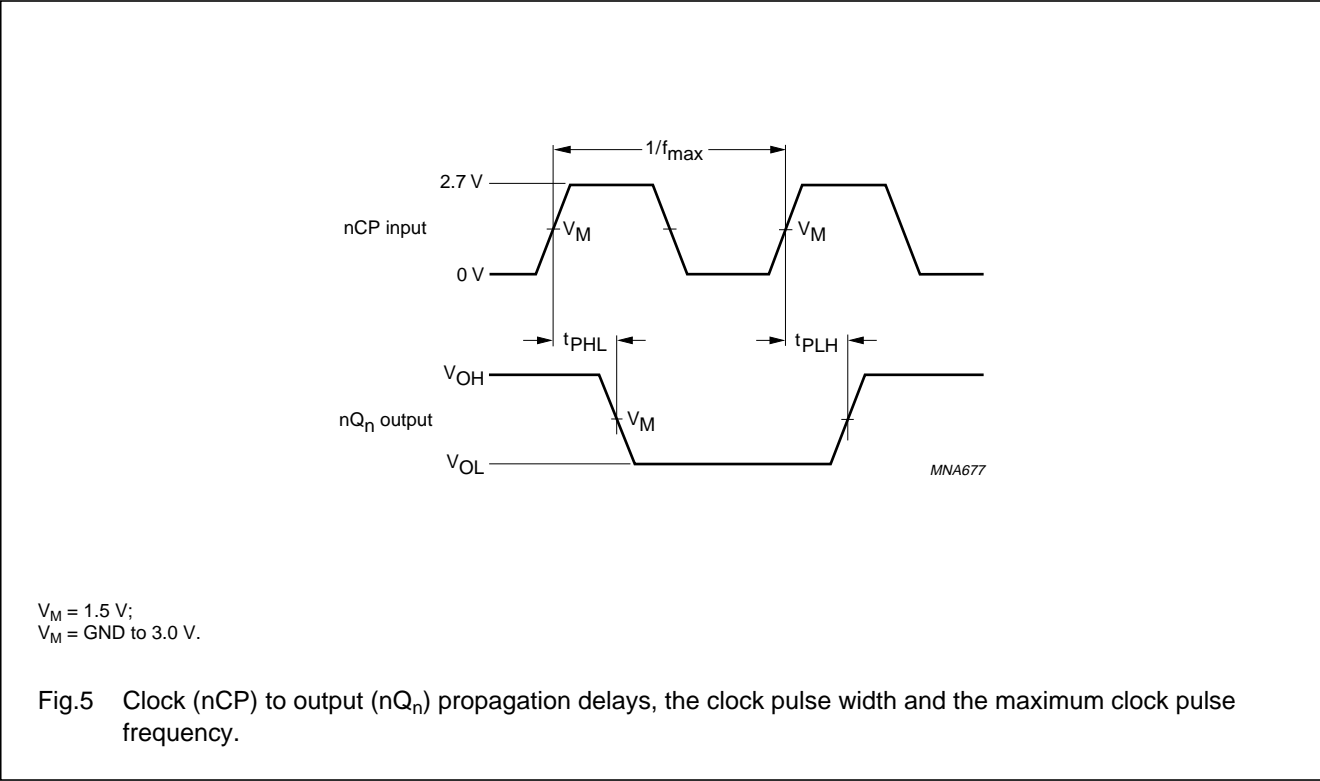
1. All typical values are measured at  $V_{CC} = 3.3$  V and  $T_{amb} = 25$  °C.



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AC WAVEFORMS



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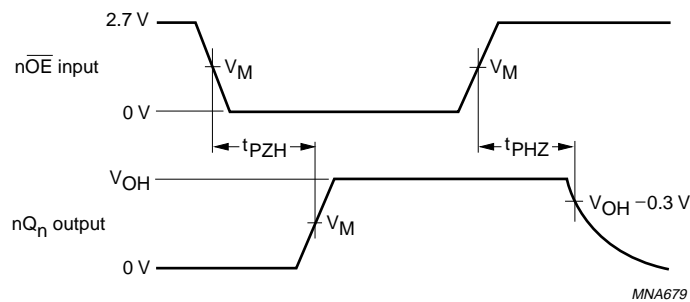


Fig.7 3-state output enable time to HIGH level and output disable time from HIGH level.

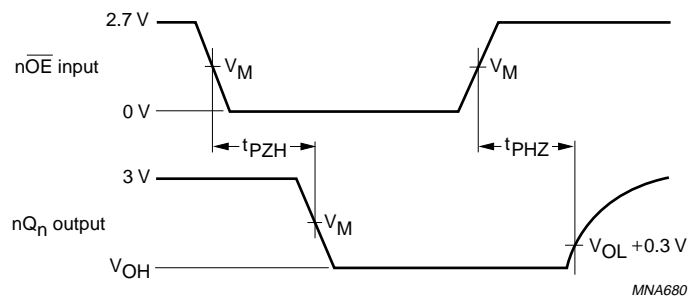
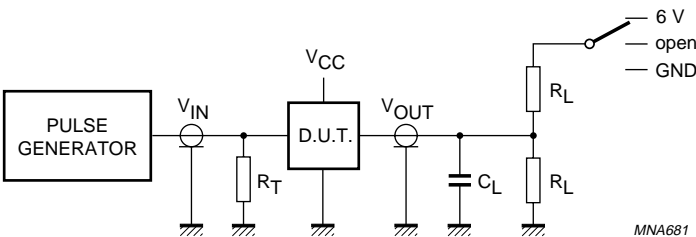


Fig.8 3-state output enable time to LOW level and output disable time from LOW level.

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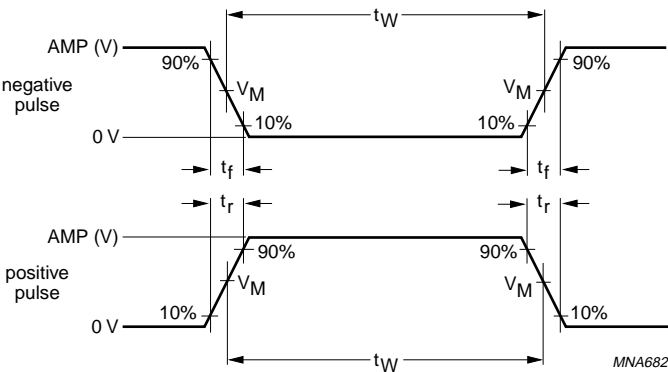
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TEST	SWITCH
$t_{PLH}/t_{PHL}$	open
$t_{PLZ}/t_{PZL}$	6 V
$t_{PHZ}/t_{PZH}$	GND

Definitions for test circuit:  
 $R_L$  = Load resistor.  
 $C_L$  = Load capacitance including jig and probe capacitance.  
 $R_T$  = Termination resistance should be equal to the output impedance  $Z_o$  of the pulse generator.

Fig.9 Load circuitry for switching times.



INPUT PULSE REQUIREMENTS				
AMPLITUDE	PULSE RATE	$t_w$	$t_r$	$t_f$
2.7 V	$\leq 10$ MHz	500 ns	$\leq 2.5$ ns	$\leq 2.5$ ns

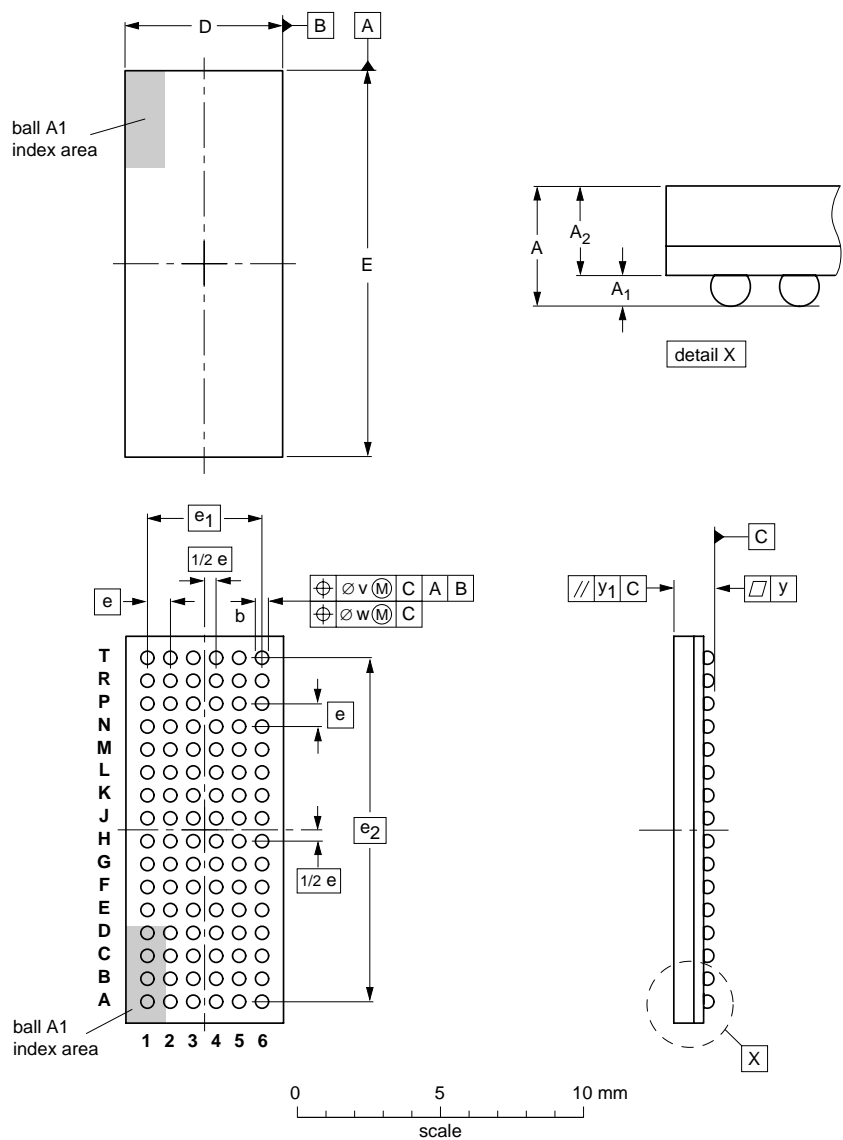
Fig.10 Input pulse definition.

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PACKAGE OUTLINE

LFBGA96: plastic low profile fine-pitch ball grid array package; 96 balls; body 13.5 x 5.5 x 1.05 mm SOT536-1



DIMENSIONS (mm are the original dimensions)

UNIT	A <sub>max.</sub>	A <sub>1</sub>	A <sub>2</sub>	b	D	E	e	e <sub>1</sub>	e <sub>2</sub>	v	w	y	y <sub>1</sub>
mm	1.5	0.41 0.31	1.2 0.9	0.51 0.41	5.6 5.4	13.6 13.4	0.8	4	12	0.15	0.1	0.1	0.2

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT536-1						00-03-04 03-02-05

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#### DATA SHEET STATUS

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I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
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